1. Record Nr.	UNINA9911019099703321
Titolo	Electron microscopy : principles and fundamentals / / edited by S. Amelinckx ... [et al.]
Pubbl/distr/stampa	Weinheim [Germany], : VCH, a Wiley Co., 1997
ISBN	9786611842550 9781281842558 1281842559 9783527614561 3527614567 9783527614554 3527614559
Descrizione fisica	1 online resource (529 p.)
Altri autori (Persone)	AmelinckxS
Disciplina	502.825
Soggetti	Electron microscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Electron Microscopy Principles and Fundamentals; Contents; Introduction; 1 Stationary Beam Methods; 1.1 Transmission Electron Microscopy; 1.1.1 Diffraction Contrast Transmission Electron Microscopy; 1.1.2 High-Resolution Electron Microscopy; 1.2 Reflection Electron Microscopy; 1.3 Electron Energy-Loss Spectroscopy Imaging; 1.4 High Voltage Electron Microscopy; 1.5 Convergent Beam Electron Diffraction; 1.6 Low-Energy Electron Microscopy; 1.7 Lorentz Microscopy; 1.8 Electron Holography Methods; 1.9 Spin-Polarized Low-Energy; 2 Scanning Beam Methods; 2.1 Scanning Reflection Electron Microscopy 2.2 Scanning Transmission Electron Microscopy2.3 Scanning-Transmission Electron Microscopy : Z Contrast; 2.4 Scanning Auger Microscopy (SAM) and Imaging X-Ray Photoelectron Microscopy (XPS); 2.5 Scanning Microanalysis; 2.6 Imaging Secondary Ion Mass Spectrometry; 2.7 Scanning Electron Microscopy with Polarization Analysis (SEMPA); Index
Sommario/riassunto	Derived from the successful three-volume Handbook of Microscopy,

this book provides a broad survey of the physical fundamentals and principles of all modern techniques of electron microscopy. This reference work on the method most often used for the characterization of surfaces offers a competent comparison of the feasibilities of the latest developments in this field of research.Topics include:* Stationary Beam Methods: Transmission Electron Microscopy/ Electron Energy Loss Spectroscopy/ Convergent Electron Beam Diffraction/ Low Energy Electron Microscopy/ Electron Holographic Met